



CERTIFICATE OF MAILING
37 C.F.R. § 1.8

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April 29, 2005
Date

May Paul
Signature

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

MATTHEW A. PURDY

Serial No.: 10/634,013

Filed: August 4, 2003

For: DYNAMIC METROLOGY SAMPLING
METHODS, AND SYSTEM FOR
PERFORMING SAME

Group Art Unit: 2125

Examiner: Unknown

Atty. Dkt. No.: 2000.108900/TT5512

Customer No.: 23720

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record. Because the filing date of the present application is after June 30, 2003, copies of the listed U.S. patents are not included. Copies of the listed foreign patent document and journal article are enclosed for the convenience of the Examiner.

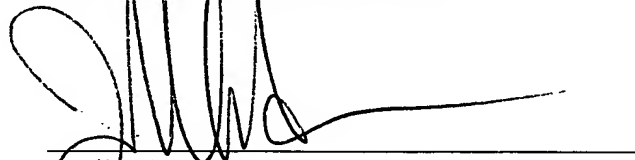
In accordance with 37 C.F.R. §§ 1.97(g),(h), this Information Disclosure Statement is not to be construed as a representation that a search has been made, and is not to be construed to be an admission that the information cited is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56(b).

In accordance with 37 C.F.R. § 1.97(e)(1), Applicant hereby certifies that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the present statement, as evidenced by the date of the enclosed PCT Search Report.

Applicant respectfully requests that the listed documents be made of record in the present case.

Respectfully submitted,

WILLIAMS, MORGAN & AMERSON
CUSTOMER NUMBER 23720

A handwritten signature in dark ink, appearing to read 'J. Mike Amerson', is written over a horizontal line.

Date: April 29, 2005

J. Mike Amerson
Reg. No. 35,426
10333 Richmond, Suite 1100
Houston, Texas 77042
(713) 934-4055
(713) 934-7011 (facsimile)

ATTORNEY FOR APPLICANT

Form PTO-1449 (modified)

List of Patents and Publications for Applicants

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Atty. Docket No.
2000.108900/TT5512Serial No.
10/634,013Applicant
Matthew A. PurdyFiling Date:
August 4, 2003Group:
2125U.S. Patent Documents
*See Page 1*Foreign Patent Documents
*See Page 1*Other Art
See Page 1

U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.
	A1	5,541,846	7/30/96	Secrest	364	468.17	
	A2	6,442,496 B1	8/27/02	Pasady <i>et al.</i>	702	83	
	A3						
	A4						
	A5						

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1	WO 02/23289 A2	3/21/02	PCT	G05B	13/02	Yes
	B2						
	B3						

Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C1	Williams <i>et al.</i> , "Optimized Sample Planning for Wafer Defect Inspection," IEEE, pp. 43-46, 1999
	C2	
	C3	

EXAMINER:

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.